

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/629,430	CHOI ET AL.	
Examiner	Art Unit	
Scott Geyer	2812	

SEARCHED						
Class	Subclass	Date	Examiner			
search	updated	9/30/2006	SBG			
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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	terference arch	9/30/2006	SBG		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
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